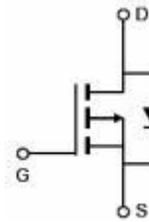
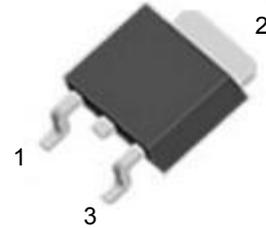


## CTKD50P04

### Features

- $V_{DS} = -40V$ ,  $I_D = -50A$   
 $R_{DS(on)} < 15\ m\Omega$  @  $V_{GS} = -10V$   
 $R_{DS(on)} < 20\ m\Omega$  @  $V_{GS} = -4.5V$
- Green Device Available
- Low Gate Charge
- Advanced High Cell Density Trench Technology
- 100% EAS Guaranteed

TO-252



1. Gate (G)
2. Drain (D)
3. Source (S)

### Absolute Maximum Ratings ( $T_A = 25^\circ C$ , unless otherwise noted)

Parameter	Symbol	Value	Unit
Drain-Source Voltage	$V_{DS}$	-40	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V
Continuous Drain Current	$I_D$	$T_C = 25^\circ C$	-50
		$T_C = 100^\circ C$	-35
Pulsed Drain Current <sup>1</sup>	$I_{DM}$	-200	A
Single Pulse Avalanche Energy <sup>2</sup>	<b>EAS</b>	80	mJ
Total Power Dissipation	$T_C = 25^\circ C$	$P_D$	55
Operating Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 to 150	$^\circ C$

### Thermal Characteristics

Parameter	Symbol	Value	Unit
Thermal Resistance from Junction-to-Ambient <sup>3</sup>	$R_{\theta JA}$	61	$^\circ C/W$
Thermal Resistance from Junction-to-Case	$R_{\theta JC}$	2.27	$^\circ C/W$

**Electrical Characteristics (T<sub>J</sub> = 25°C, unless otherwise noted)**

40V P-Channel MOSFET

Parameter	Symbol	Test Conditions	Min.	Typ.	Max.	Unit
<b>Static Characteristics</b>						
Drain-Source Breakdown Voltage	<b>V<sub>(BR)DSS</sub></b>	V <sub>GS</sub> = 0V, I <sub>D</sub> = -250μA	-40	-	-	V
Gate-body Leakage current	<b>I<sub>GSS</sub></b>	V <sub>DS</sub> = 0V, V <sub>GS</sub> = ±20V	-	-	±100	nA
Zero Gate Voltage Drain Current	T <sub>J</sub> =25°C	V <sub>DS</sub> = -40V, V <sub>GS</sub> = 0V	-	-	1	μA
	T <sub>J</sub> =100°C		-	-	100	
Gate-Threshold Voltage	<b>V<sub>GS(th)</sub></b>	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = -250μA	-1.0	-1.6	-2.5	V
Drain-Source On-Resistance <sup>4</sup>	<b>R<sub>DS(on)</sub></b>	V <sub>GS</sub> = -10V, I <sub>D</sub> = -16A	-	12	15	mΩ
		V <sub>GS</sub> = -4.5V, I <sub>D</sub> = -10A	-	16	20	
Forward Transconductance <sup>4</sup>	<b>g<sub>fs</sub></b>	V <sub>DS</sub> = -10V, I <sub>D</sub> = -16A	-	44	-	S
<b>Dynamic Characteristics<sup>5</sup></b>						
Input Capacitance	<b>C<sub>iss</sub></b>	V <sub>DS</sub> = -20V, V <sub>GS</sub> = 0V, f = 1MHz	-	3050	-	pF
Output Capacitance	<b>C<sub>oss</sub></b>		-	282	-	
Reverse Transfer Capacitance	<b>C<sub>rss</sub></b>		-	230	-	
Gate Resistance	<b>R<sub>g</sub></b>	f = 1MHz	-	9	-	Ω
<b>Switching Characteristics<sup>5</sup></b>						
Total Gate Charge	<b>Q<sub>g</sub></b>	V <sub>GS</sub> = -10V, V <sub>DS</sub> = -20V, I <sub>D</sub> = -16A	-	28	-	nC
Gate-Source Charge	<b>Q<sub>gs</sub></b>		-	8	-	
Gate-Drain Charge	<b>Q<sub>gd</sub></b>		-	8.5	-	
Turn-on Delay Time	<b>t<sub>d(on)</sub></b>	V <sub>GS</sub> = -10V, V <sub>DD</sub> = -15V, R <sub>G</sub> = 3Ω, I <sub>D</sub> = -16A	-	38	-	ns
Rise Time	<b>t<sub>r</sub></b>		-	31	-	
Turn-off Delay Time	<b>t<sub>d(off)</sub></b>		-	90	-	
Fall Time	<b>t<sub>f</sub></b>		-	9.2	-	
<b>Drain-Source Body Diode Characteristics</b>						
Diode Forward Voltage <sup>4</sup>	<b>V<sub>SD</sub></b>	I <sub>S</sub> = -1A, V <sub>GS</sub> = 0V	-	-	-1.2	V
Continuous Source Current	T <sub>C</sub> =25°C	<b>I<sub>S</sub></b>	-	-	-50	A

**Notes:**

1. Repetitive rating, pulse width limited by junction temperature T<sub>J(MAX)</sub>=150°C.
2. The EAS data shows Max. rating . The test condition is V<sub>DD</sub>= -25V, V<sub>GS</sub>= -10V, L=0.1mH, I<sub>AS</sub>= -50A.
3. The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper, The value in any given application depends on the user's specific board design.
4. The data tested by pulsed , pulse width ≤ 300us , duty cycle ≤ 2%.
5. This value is guaranteed by design hence it is not included in the production test..

**Typical Characteristics**

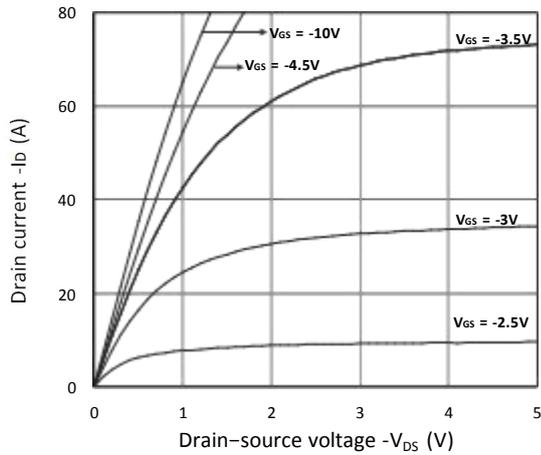


Figure 1. Output Characteristics

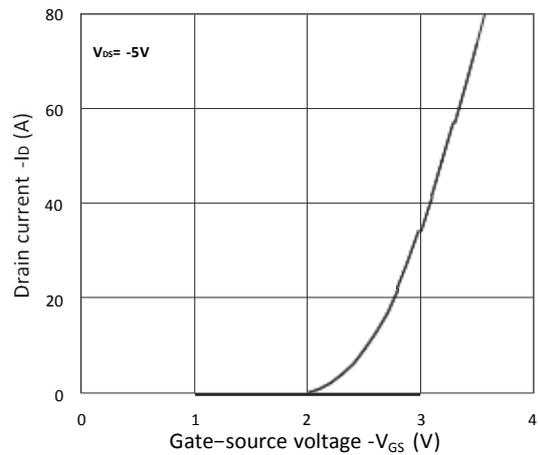


Figure 2. Transfer Characteristics

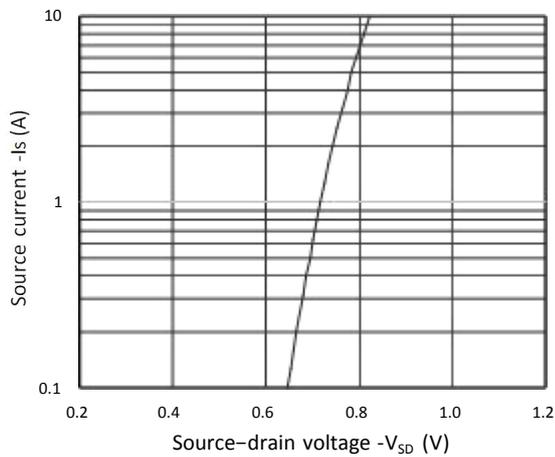


Figure 3. Forward Characteristics of Reverse

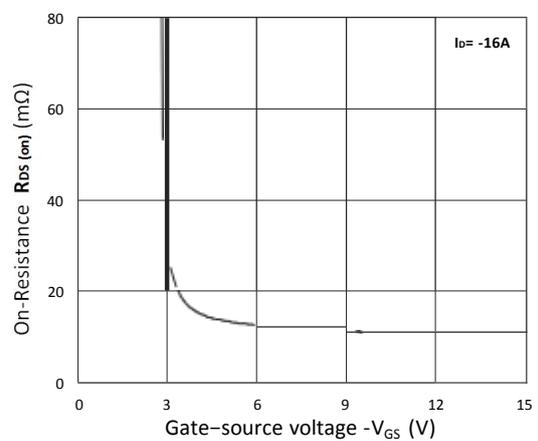


Figure 4.  $R_{DS(ON)}$  vs.  $V_{GS}$

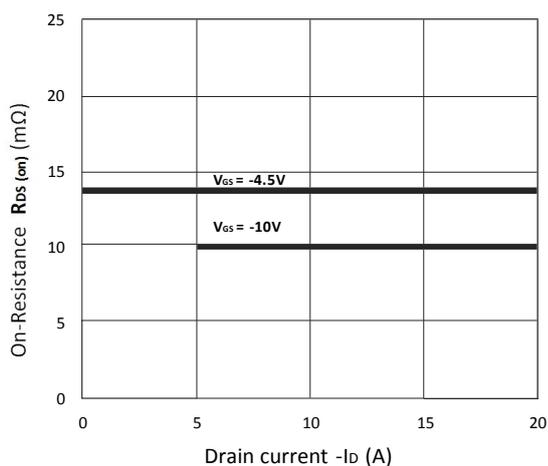


Figure 5.  $R_{DS(ON)}$  vs.  $I_D$

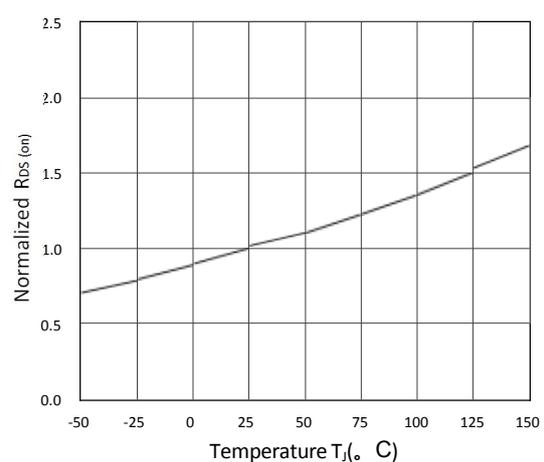


Figure 6. Normalized  $R_{DS(on)}$  vs. Temperature

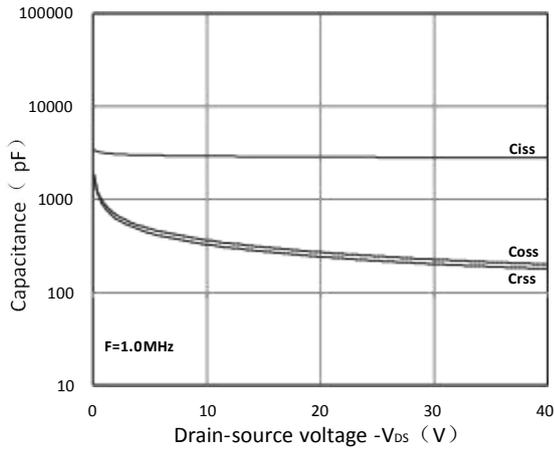


Figure 7. Capacitance Characteristics

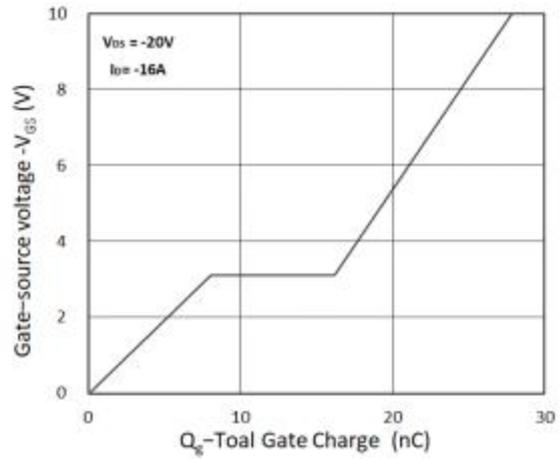


Figure 8. Gate Charge Characteristics

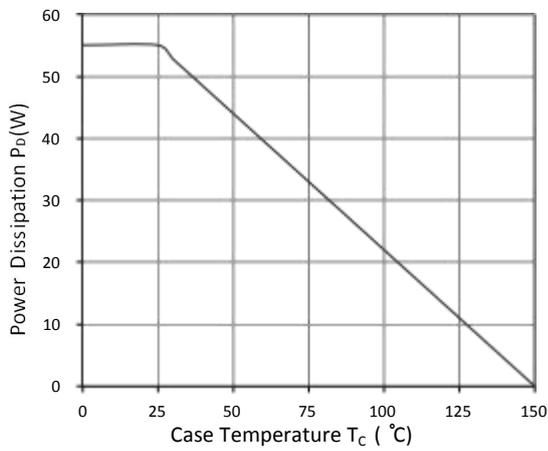


Figure 9. Power Dissipation

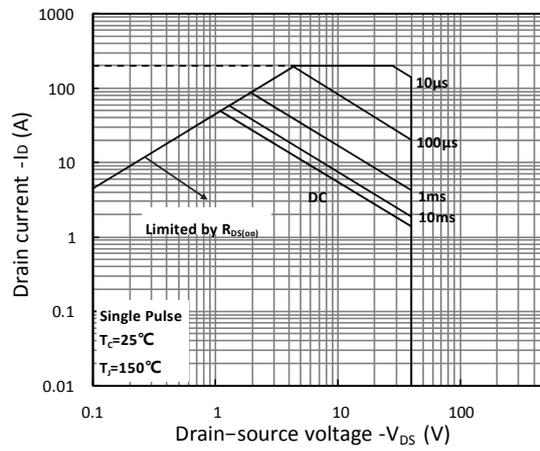


Figure 10. Safe Operating Area

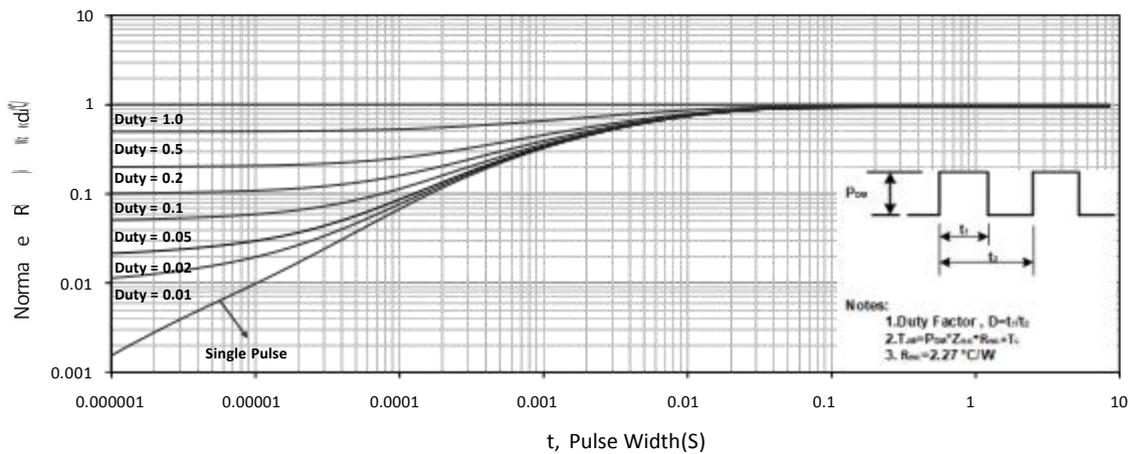
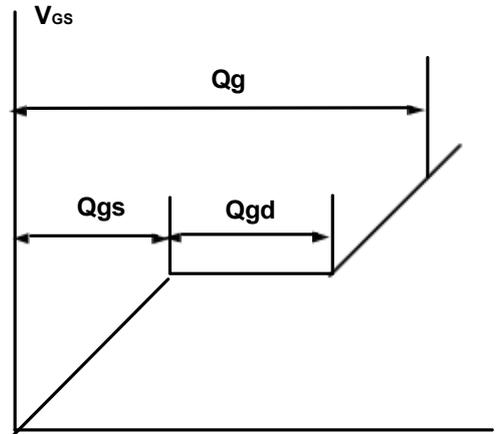
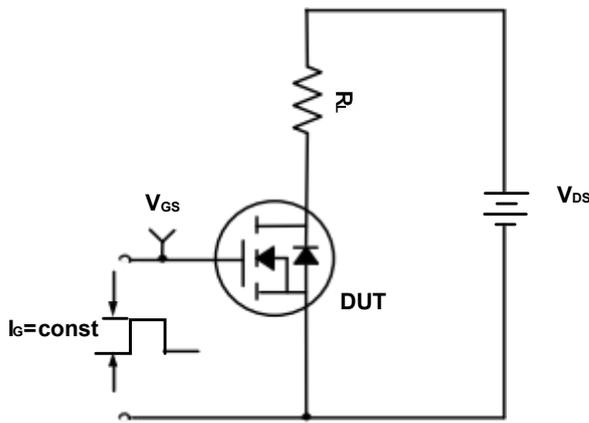
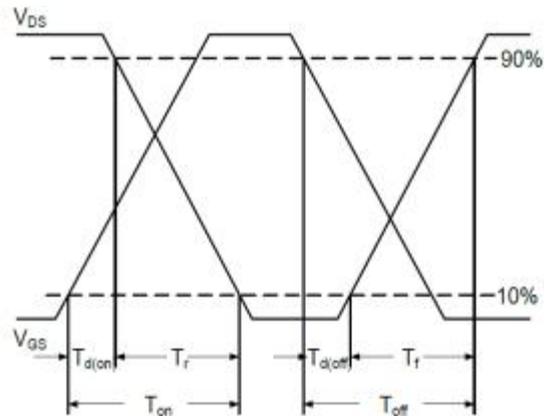
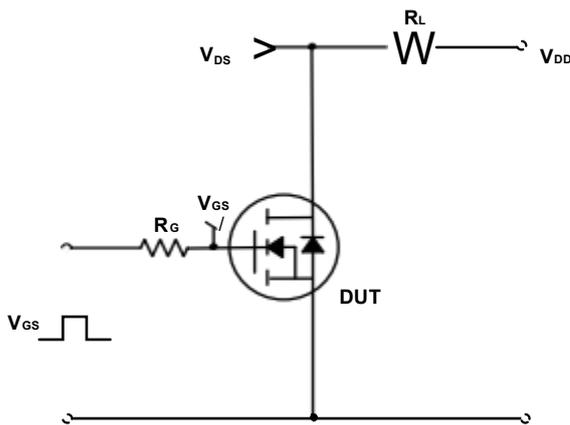


Figure 11. Normalized Maximum Transient Thermal Impedance

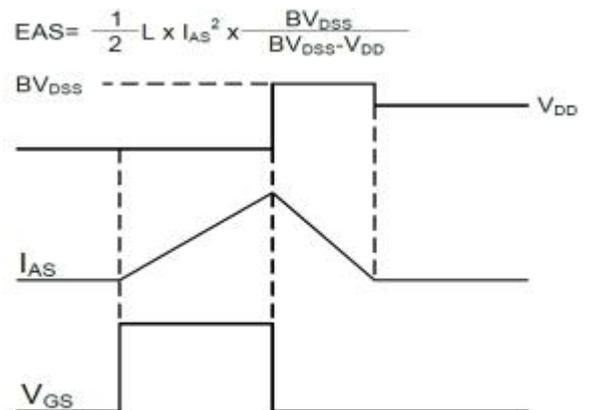
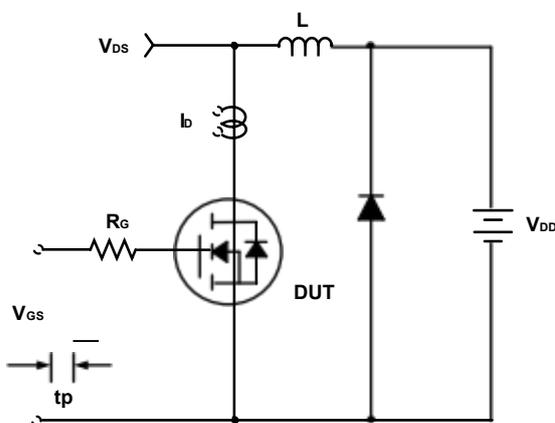
**Test Circuit**



**Figure A. Gate Charge Test Circuit & Waveforms**

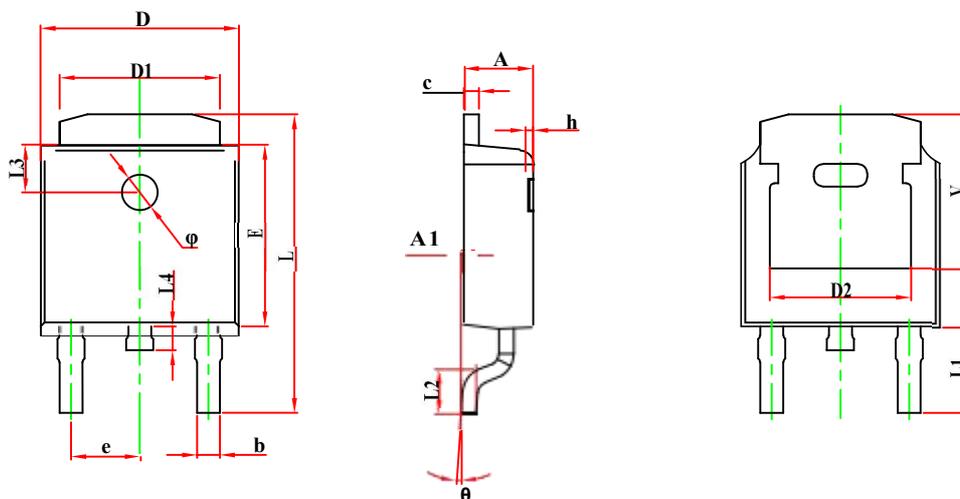


**Figure B. Switching Test Circuit & Waveforms**



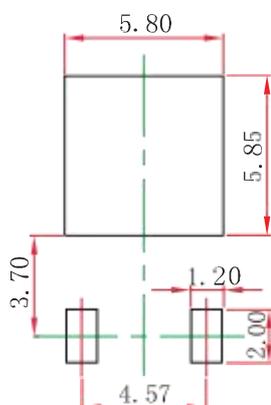
**Figure C. Unclamped Inductive Switching Circuit & Waveforms**

## Package Dimension



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	2.200	2.400	0.087	0.094
A1	0.000	0.127	0.000	0.005
b	0.700	0.860	0.025	0.030
c	0.460	0.580	0.018	0.023
D	6.500	6.700	0.256	0.264
D1	5.100	5.460	0.201	0.215
D2	4.830 REF.		0.190 REF.	
E	6.000	6.300	0.236	0.244
e	2.186	2.386	0.086	0.094
L	9.712	10.312	0.382	0.406
L1	2.900 REF.		0.114 REF.	
L2	1.400	1.700	0.055	0.067
L3	1.600 REF.		0.063 REF.	
L4	0.600	1.000	0.024	0.039
φ	1.100	1.300	0.043	0.051
θ	0°	8°	0°	8°
h	0.000	0.300	0.000	0.012
V	5.250 REF.		0.207 REF.	

## TO-252-2L Suggest Pad Layout



### NOTE:

1. Controlling dimension: in millimeters.
2. General tolerance:  $\pm 0.05\text{mm}$ .
3. The pad layout is for reference purposes only.